

Search Notes

Application No.

10/091,472

Examiner

Quoc A. Tran

Applicant(s)

YU ET AL.

Art Unit

2176

SEARCHED

| Class | Subclass | Date | Examiner |
|---------|----------|------------|----------|
| 715 | 501.1 | 3/30/2005 | QT |
| 704 | 246 | 3/30/2005 | QT |
| 707 | 104.1 | 3/30/2005 | QT |
| updated | above | 10/6/2005 | |
| 725 | 53 | 05/13/2006 | |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|--|-----------|------|
| Inventor search check for double patent, US-PAT, US-PGPUB, EPO, JPO, Derwent, IBM_TDB, Internet search, Plus search, EIC | 3/30/2005 | QT |
| Personal Digests | 3/30/2005 | QT |
| EAST (US-PAT, US-PGPUB) See Search Histoty Printout | 10/6/2005 | |
| IEEE DataBase See Search Histoty Printout | 10/6/2005 | |
| EAST (US-PAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDB)see Search Histoty Printout | 5/13/2006 | |
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